

W-2810MR OSCILLATOR PERTURBATION TEST SYSTEM

- Automated, software-based oscillator, VCXO and TCXO temperature test system
- Measures frequency over temperature
- Parameter and curve fit characteristics are checked against easy to define QC limits
- Oscillators of different frequencies can be tested in a single temperature run
- All data is published in a Microsoft Access[™] data base
- Data can be exported to Microsoft Excel[™] for custom data analysis
- Oscillator part number can be used to set complete measurement parameters, QC limits, temperature test points and data printouts



- Electronic switching
- High speed frequency measurement
- Complete frequency perturbation testing of 512 parts in about 1.5 hours



- Chamber holds eight 64-position measurement boards for a total of 512 parts
- Socket PCBs available include 2.0x2.5, 2.5x3.2, 3.2x5, 3.5x6, 5x7, 5x7.5, 9x14, DIP (full & half)
- Measurement boards available for LVDS, PECL, ECL, CMOS, and TTL devices
- Sub PPB measurement

SPECIFICATIONS

Oscillator Frequency Range:

Temperature Stability: Temperature Uniformity:

Temperature Range:

10 KHz to 1 GHz

± 0.1° C

± 0.6° C

-55° C to 85° C (MR)

-65° C to 85° C (MR with LN₂ Boost)

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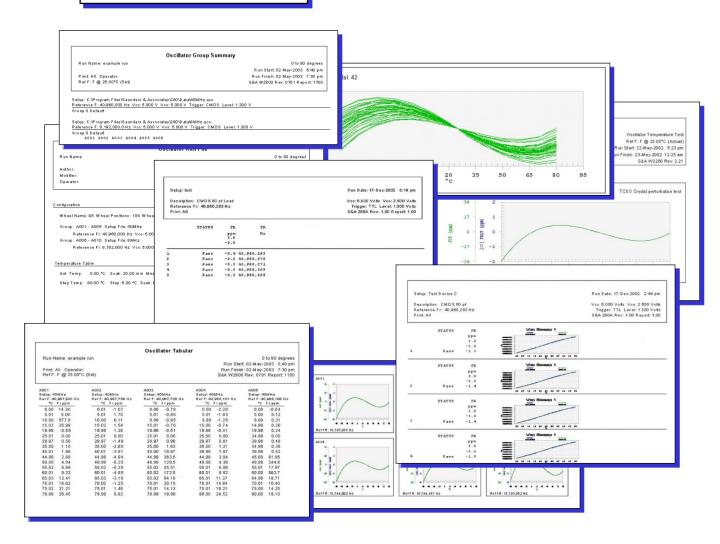
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SYSTEM CONFIGURATION

- S&A 4350MR Option 1 Temperature Test Chamber
- Eight position card cage and backplane PCB
- Frequency Counter
- DUT Power Supply

- System Controller
- S&A MFC-100 Card
- GPIB Interface
- Windows ® based System Software

SAMPLE REPORTS



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